



# RF Power Field Effect Transistor

## N-Channel Enhancement-Mode Lateral MOSFETs

Designed primarily for CW large-signal output and driver applications with frequencies up to 450 MHz. Devices are unmatched and are suitable for use in industrial, medical and scientific applications.

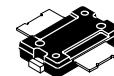
- Typical CW Performance at 220 MHz:  $V_{DD} = 50$  Volts,  $I_{DQ} = 30$  mA,  $P_{out} = 10$  Watts  
Power Gain — 23.9 dB  
Drain Efficiency — 62%
- Capable of Handling 10:1 VSWR, @ 50 Vdc, 220 MHz, 10 Watts CW Output Power

### Features

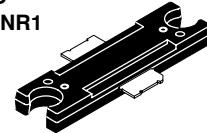
- Integrated ESD Protection
- Excellent Thermal Stability
- Facilitates Manual Gain Control, ALC and Modulation Techniques
- 200°C Capable Plastic Package
- RoHS Compliant
- TO-270-2 in Tape and Reel. R1 Suffix = 500 Units per 24 mm, 13 inch Reel.
- TO-272-2 in Tape and Reel. R1 Suffix = 500 Units per 44 mm, 13 inch Reel.

**MRF6V2010NR1**  
**MRF6V2010NBR1**

**10-450 MHz, 10 W, 50 V**  
**LATERAL N-CHANNEL**  
**BROADBAND**  
**RF POWER MOSFETs**



CASE 1265-08, STYLE 1  
TO-270-2  
PLASTIC  
MRF6V2010NR1



CASE 1337-03, STYLE 1  
TO-272-2  
PLASTIC  
MRF6V2010NBR1

**Table 1. Maximum Ratings**

Rating	Symbol	Value	Unit
Drain-Source Voltage	$V_{DSS}$	-0.5, +110	Vdc
Gate-Source Voltage	$V_{GS}$	-0.5, +10	Vdc
Storage Temperature Range	$T_{stg}$	-65 to +150	°C
Operating Junction Temperature	$T_J$	200	°C

**Table 2. Thermal Characteristics**

Characteristic	Symbol	Value (1,2)	Unit
Thermal Resistance, Junction to Case Case Temperature 81°C, 10 W CW	$R_{\theta JC}$	3.0	°C/W

- MTTF calculator available at <http://www.freescale.com/rf>. Select Tools/Software/Application Software/Calculators to access the MTTF calculators by product.
- Refer to AN1955, *Thermal Measurement Methodology of RF Power Amplifiers*. Go to <http://www.freescale.com/rf>. Select Documentation/Application Notes - AN1955.

**Table 3. ESD Protection Characteristics**

Test Methodology	Class
Human Body Model (per JESD22-A114)	2 (Minimum)
Machine Model (per EIA/JESD22-A115)	A (Minimum)
Charge Device Model (per JESD22-C101)	IV (Minimum)

**Table 4. Moisture Sensitivity Level**

Test Methodology	Rating	Package Peak Temperature	Unit
Per JESD 22-A113, IPC/JEDEC J-STD-020	3	260	°C

**Table 5. Electrical Characteristics** ( $T_C = 25^\circ\text{C}$  unless otherwise noted)

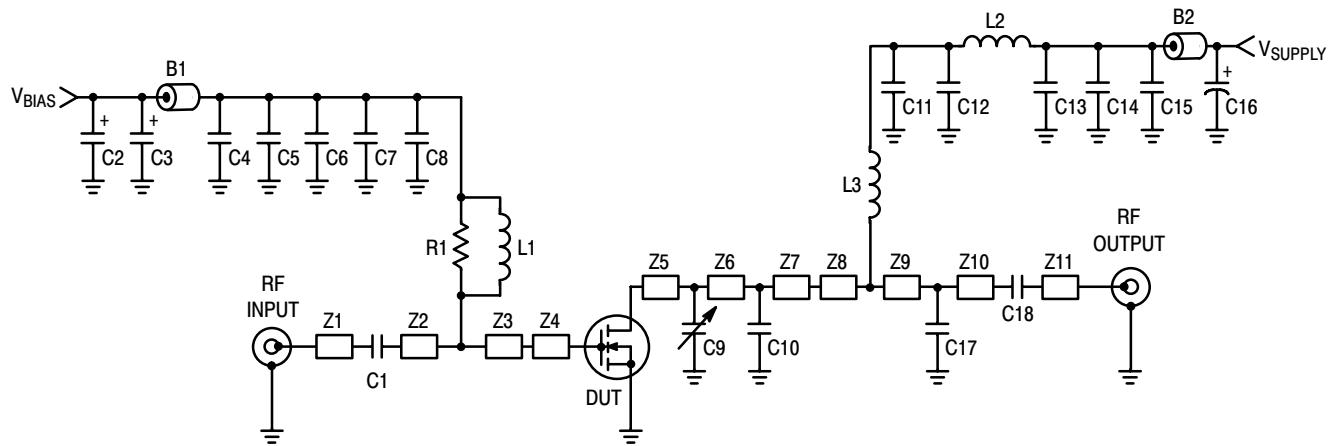
Characteristic	Symbol	Min	Typ	Max	Unit
<b>Off Characteristics</b>					
Zero Gate Voltage Drain Leakage Current ( $V_{DS} = 100 \text{ Vdc}, V_{GS} = 0 \text{ Vdc}$ )	$I_{DSS}$	—	—	2.5	mA
Zero Gate Voltage Drain Leakage Current ( $V_{DS} = 50 \text{ Vdc}, V_{GS} = 0 \text{ Vdc}$ )	$I_{DSS}$	—	—	50	$\mu\text{Adc}$
Drain-Source Breakdown Voltage ( $I_D = 5 \text{ mA}, V_{GS} = 0 \text{ Vdc}$ )	$V_{(BR)DSS}$	110	—	—	Vdc
Gate-Source Leakage Current ( $V_{GS} = 5 \text{ Vdc}, V_{DS} = 0 \text{ Vdc}$ )	$I_{GSS}$	—	—	10	$\mu\text{Adc}$
<b>On Characteristics</b>					
Gate Threshold Voltage ( $V_{DS} = 10 \text{ Vdc}, I_D = 28 \mu\text{Adc}$ )	$V_{GS(\text{th})}$	1	1.68	3	Vdc
Gate Quiescent Voltage ( $V_{DD} = 50 \text{ Vdc}, I_D = 30 \text{ mA}, \text{Measured in Functional Test}$ )	$V_{GS(Q)}$	1.5	2.68	3.5	Vdc
Drain-Source On-Voltage ( $V_{GS} = 10 \text{ Vdc}, I_D = 70 \text{ mA}$ )	$V_{DS(\text{on})}$	—	0.26	—	Vdc
<b>Dynamic Characteristics</b>					
Reverse Transfer Capacitance ( $V_{DS} = 50 \text{ Vdc} \pm 30 \text{ mV(rms)} \text{ac @ 1 MHz}, V_{GS} = 0 \text{ Vdc}$ )	$C_{rss}$	—	0.13	—	pF
Output Capacitance ( $V_{DS} = 50 \text{ Vdc} \pm 30 \text{ mV(rms)} \text{ac @ 1 MHz}, V_{GS} = 0 \text{ Vdc}$ )	$C_{oss}$	—	7.3	—	pF
Input Capacitance ( $V_{DS} = 50 \text{ Vdc} \pm 30 \text{ mV(rms)} \text{ac @ 1 MHz}, V_{GS} = 0 \text{ Vdc}$ )	$C_{iss}$	—	16.3	—	pF

**Functional Tests** (In Freescale Test Fixture, 50 ohm system)  $V_{DD} = 50 \text{ Vdc}$ ,  $I_{DQ} = 30 \text{ mA}$ ,  $P_{out} = 10 \text{ W}$ ,  $f = 220 \text{ MHz}$ , CW

Power Gain	$G_{ps}$	22.5	23.9	25.5	dB
Drain Efficiency	$\eta_D$	58	62	—	%
Input Return Loss	IRL	—	-14	-9	dB



ATTENTION: The MRF6V2010N and MRF6V2010NB are high power devices and special considerations must be followed in board design and mounting. Incorrect mounting can lead to internal temperatures which exceed the maximum allowable operating junction temperature. Refer to Freescale Application Note AN3263 (for bolt down mounting) or AN1907 (for solder reflow mounting) **PRIOR TO STARTING SYSTEM DESIGN** to ensure proper mounting of these devices.

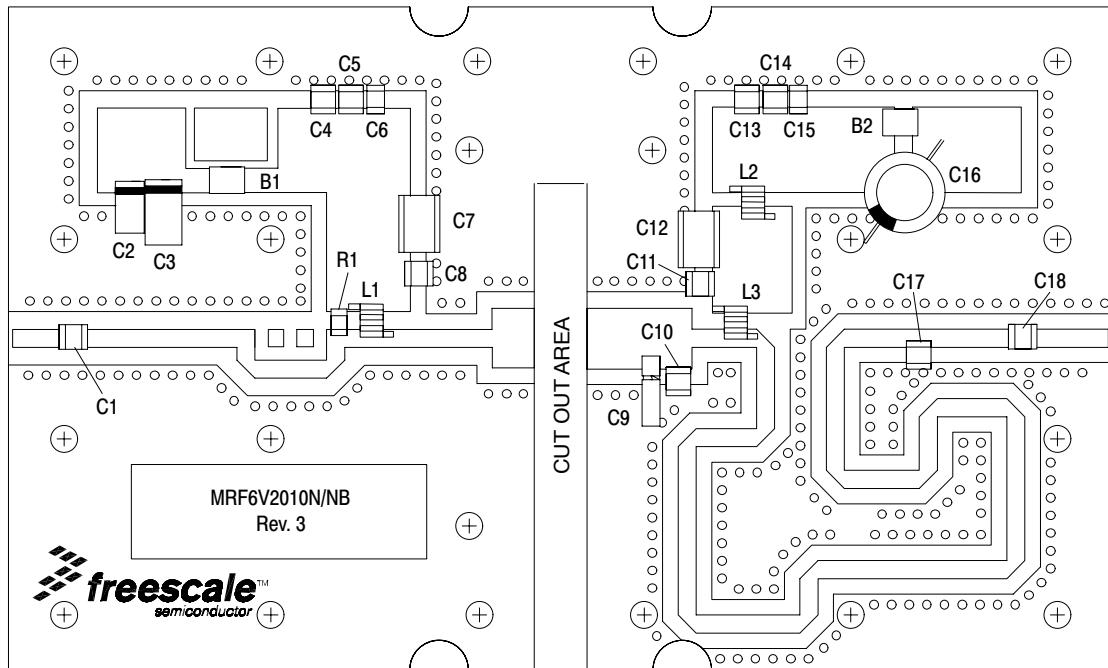


Z1	0.235" x 0.082" Microstrip	Z7	0.062" x 0.270" Microstrip
Z2	1.190" x 0.082" Microstrip	Z8	0.198" x 0.082" Microstrip
Z3	0.619" x 0.082" Microstrip	Z9	5.600" x 0.082" Microstrip
Z4	0.190" x 0.270" Microstrip	Z10	0.442" x 0.082" Microstrip
Z5	0.293" x 0.270" Microstrip	Z11	0.341" x 0.082" Microstrip
Z6	0.120" x 0.270" Microstrip	PCB	Arlon GX-0300-55-22, 0.030", $\epsilon_r = 2.55$

Figure 1. MRF6V2010NR1(NBR1) Test Circuit Schematic

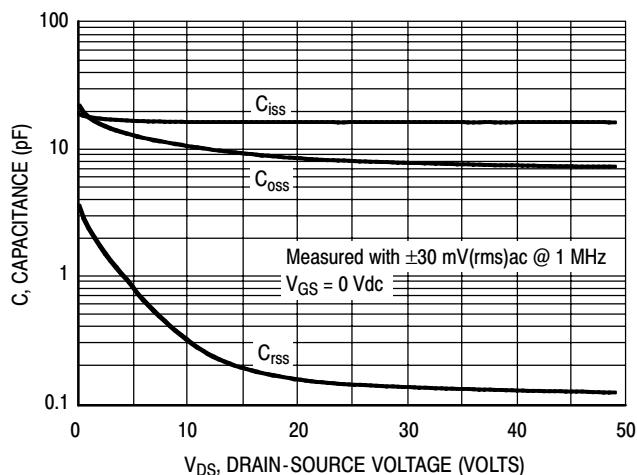
Table 6. MRF6V2010NR1(NBR1) Test Circuit Component Designations and Values

Part	Description	Part Number	Manufacturer
B1, B2	95 $\Omega$ , 100 MHz Long Ferrite Beads	2743021447	Fair-Rite
C1, C8, C11, C18	1000 pF Chip Capacitors	ATC100B102JT50XT	ATC
C2	10 $\mu$ F, 35 V Tantalum Capacitor	T491D106K035AT	Kemet
C3	22 $\mu$ F, 35 V Tantalum Capacitor	T491X226K035AT	Kemet
C4, C13	39 K pF Chip Capacitors	ATC200B393KT50XT	ATC
C5, C14	22 K pF Chip Capacitors	ATC200B223KT50XT	ATC
C6, C15	0.1 $\mu$ F Chip Capacitors	CDR33BX104AKYS	Kemet
C7, C12	2.2 $\mu$ F, 50 V Chip Capacitors	C1825C225J5RAC	Kemet
C9	0.6-4.5 pF Variable Capacitor, Gigatrim	27271SL	Johanson
C10	12 pF Chip Capacitor	ATC100B120JT500XT	ATC
C16	470 $\mu$ F, 63 V Electrolytic Capacitor	ESMG630ELL471MK205	United Chemi-Con
C17	27 pF Chip Capacitor	ATC100B270JT500XT	ATC
L1	17.5 nH Inductor	B06T	CoilCraft
L2, L3	82 nH Inductors	1812SMS-82NJ	CoilCraft
R1	120 $\Omega$ , 1/4 W Chip Resistor	CRCW12061200FKTA	Vishay

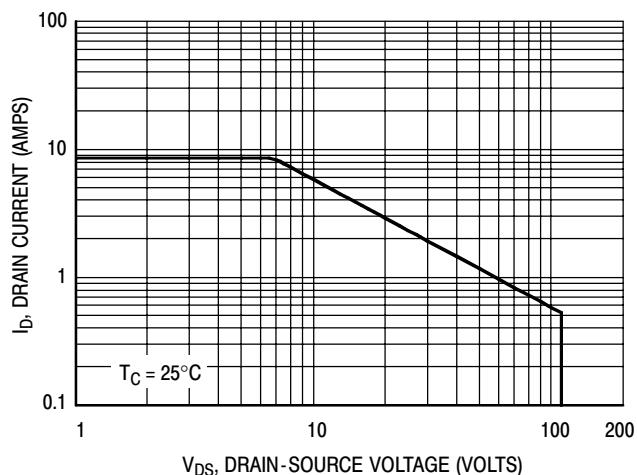


**Figure 2. MRF6V2010NR1(NBR1) Test Circuit Component Layout**

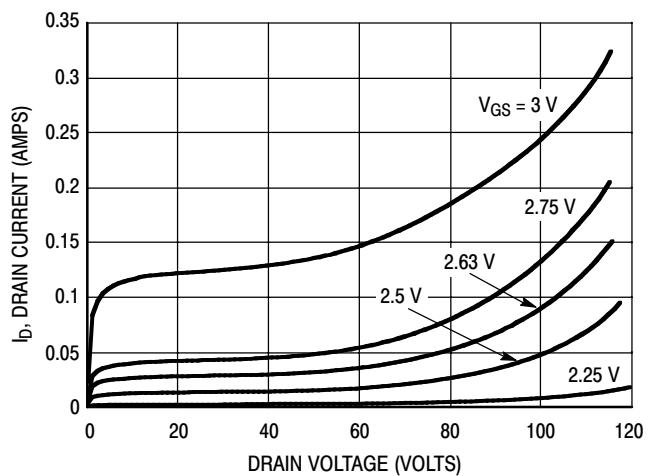
## TYPICAL CHARACTERISTICS



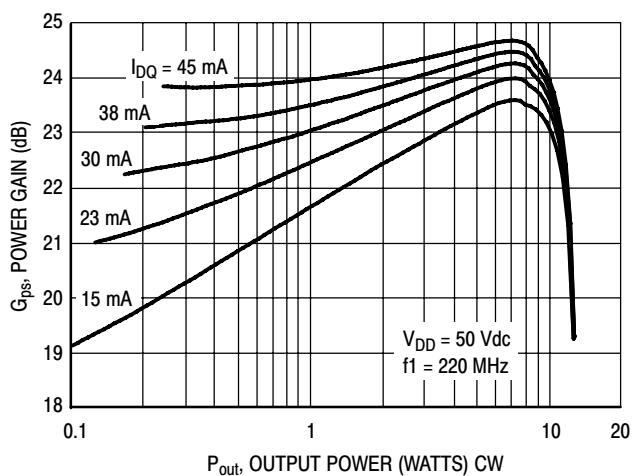
**Figure 3. Capacitance versus Drain-Source Voltage**



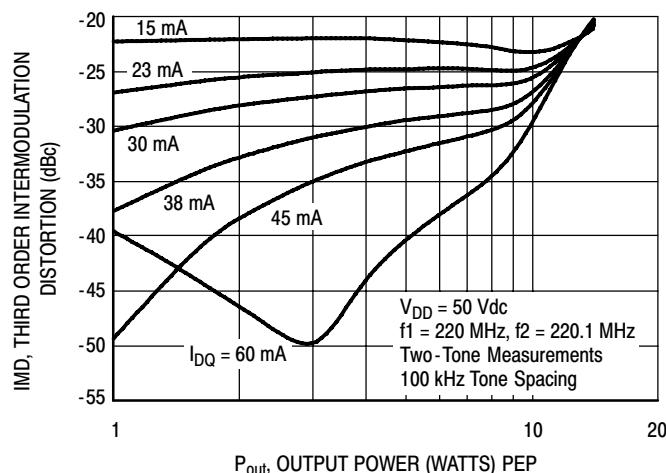
**Figure 4. DC Safe Operating Area**



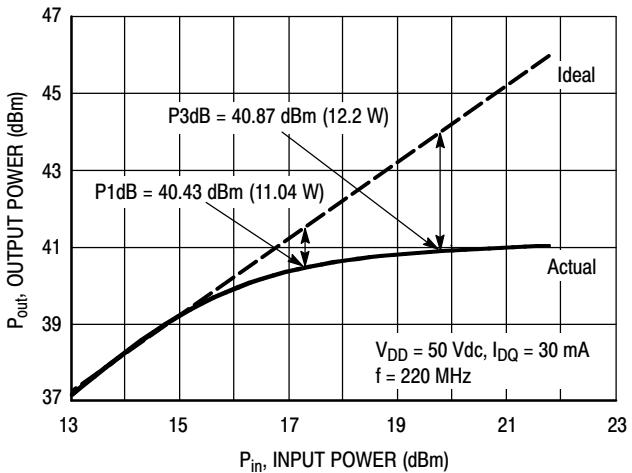
**Figure 5. DC Drain Current versus Drain Voltage**



**Figure 6. CW Power Gain versus Output Power**

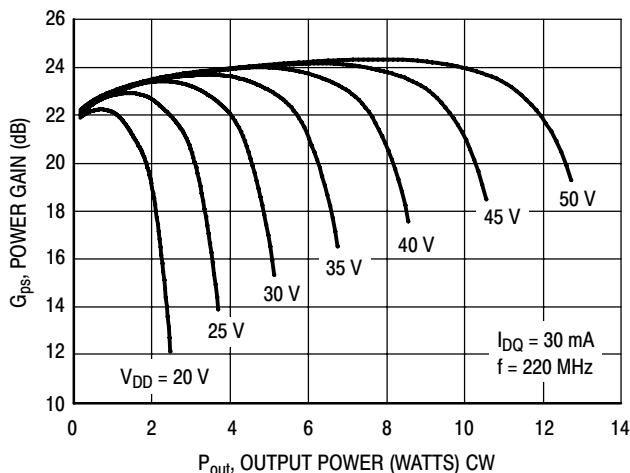


**Figure 7. Third Order Intermodulation Distortion versus Output Power**

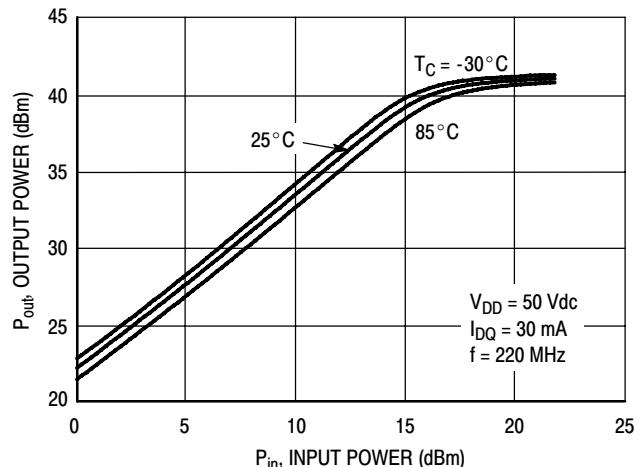


**Figure 8. CW Output Power versus Input Power**

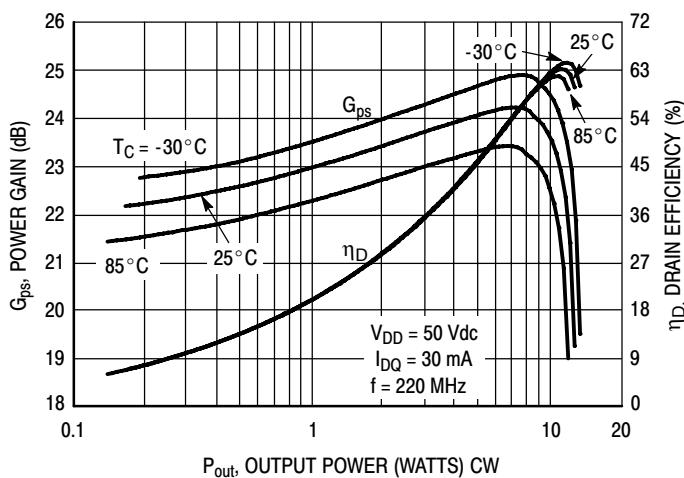
## TYPICAL CHARACTERISTICS



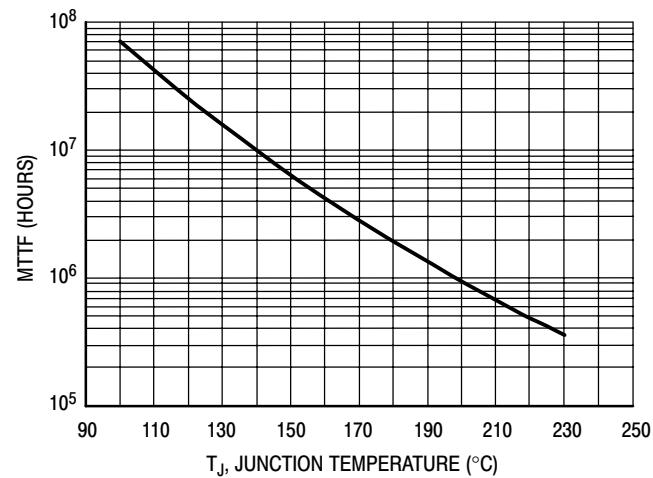
**Figure 9. Power Gain versus Output Power**



**Figure 10. Power Output versus Power Input**



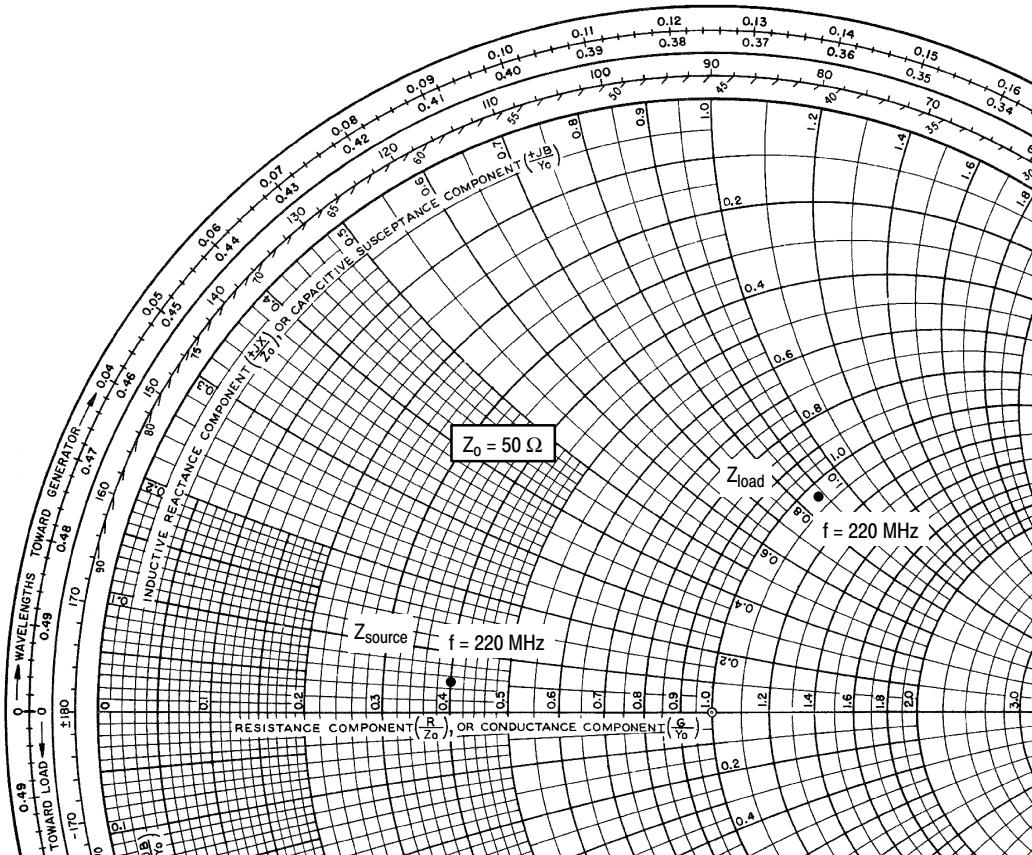
**Figure 11. Power Gain and Drain Efficiency versus CW Output Power**



This above graph displays calculated MTTF in hours when the device is operated at  $V_{DD} = 50$  Vdc,  $P_{out} = 10$  W CW, and  $\eta_D = 62\%$ .

MTTF calculator available at <http://www.freescale.com/rf>. Select Tools/Software/Application Software/Calculators to access the MTTF calculators by product.

**Figure 12. MTTF versus Junction Temperature**

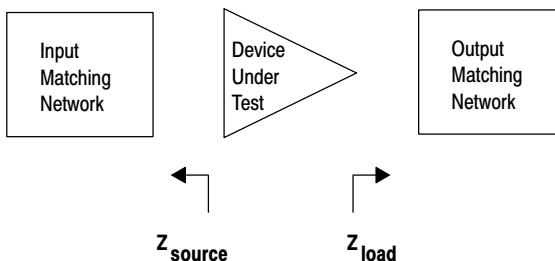


$V_{DD} = 50 \text{ Vdc}, I_{DQ} = 30 \text{ mA}, P_{out} = 10 \text{ W CW}$

$f$ MHz	$Z_{\text{source}}$ $\Omega$	$Z_{\text{load}}$ $\Omega$
220	$20 + j25$	$75 + j44$

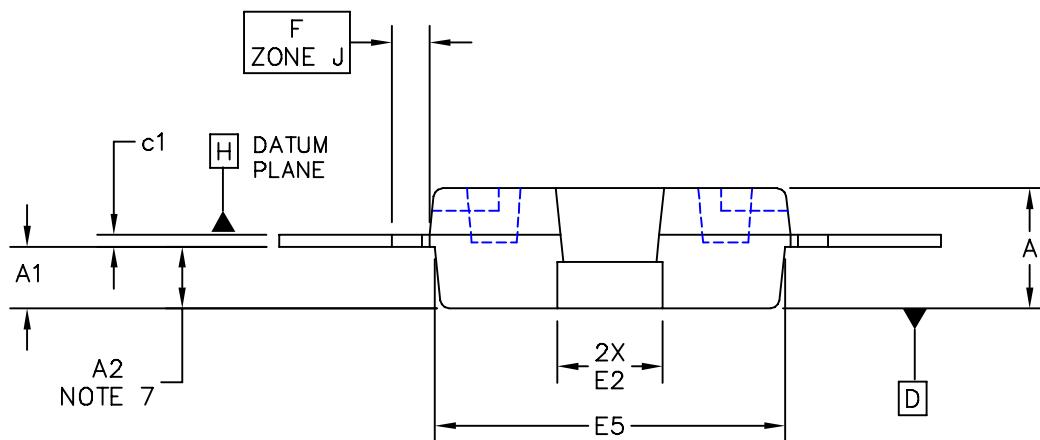
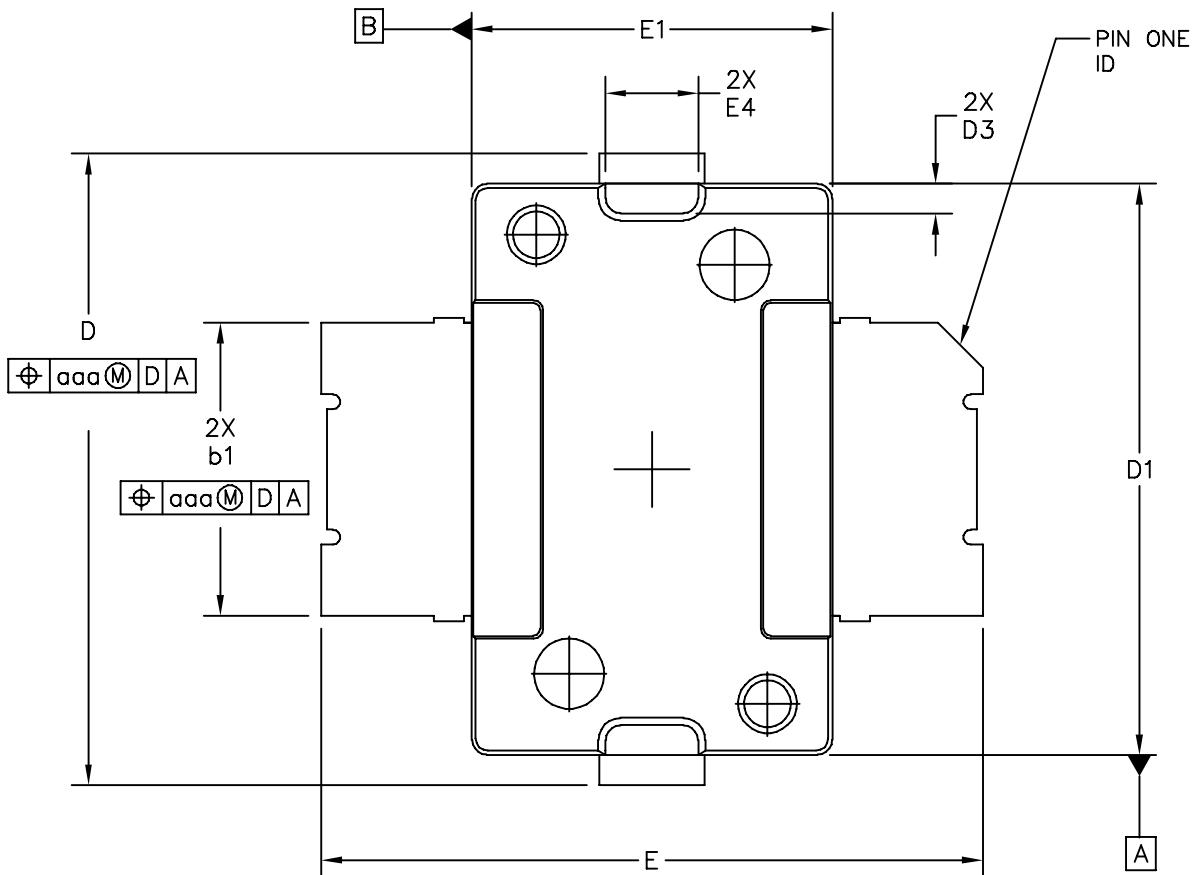
$Z_{\text{source}}$  = Test circuit impedance as measured from gate to ground.

$Z_{\text{load}}$  = Test circuit impedance as measured from drain to ground.

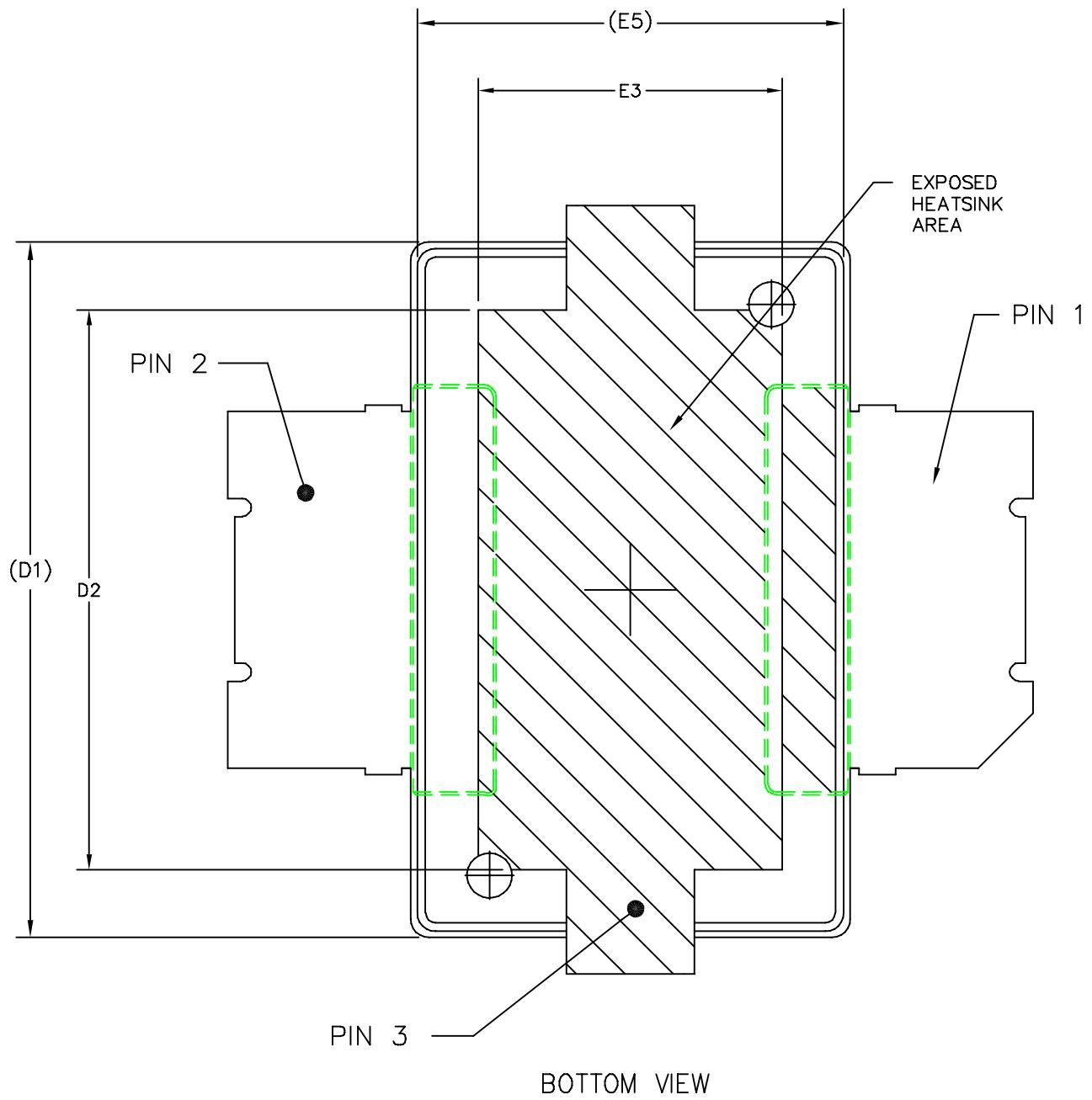


**Figure 13. Series Equivalent Source and Load Impedance**

## PACKAGE DIMENSIONS



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TITLE:	TO-270 SURFACE MOUNT	DOCUMENT NO: 98ASH98117A	REV: J	CASE NUMBER: 1265-08 01 APR 2005
		STANDARD: NON-JEDEC		



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TITLE:  TO-270 SURFACE MOUNT	DOCUMENT NO: 98ASH98117A	REV: J
	CASE NUMBER: 1265-08	01 APR 2005
	STANDARD: NON-JEDEC	

MRF6V2010NR1 MRF6V2010NBR1

## NOTES:

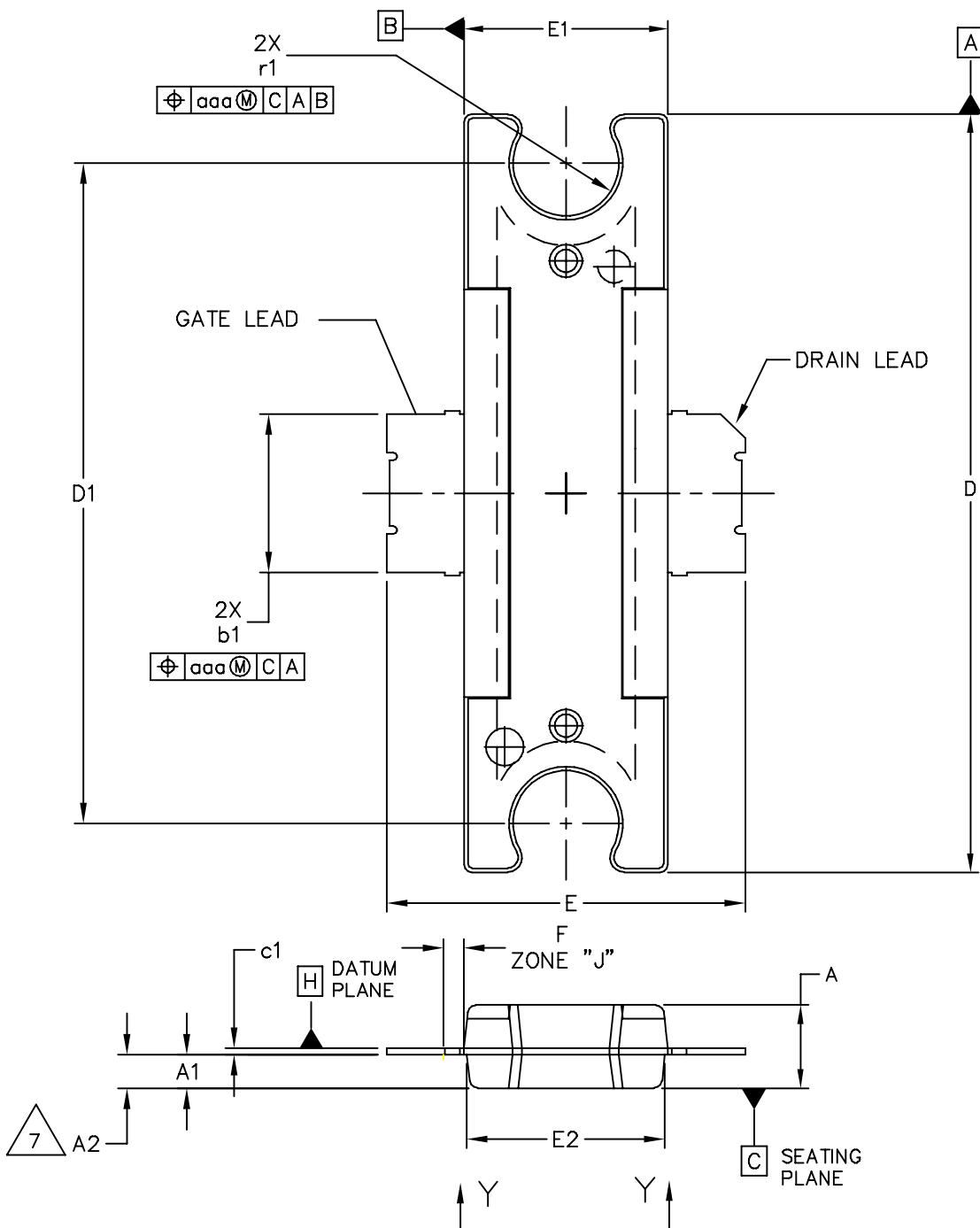
1. CONTROLLING DIMENSION: INCH
2. INTERPRET DIMENSIONS AND TOLERANCES PER ASME Y14.5M-1994.
3. DATUM PLANE -H- IS LOCATED AT TOP OF LEAD AND IS COINCIDENT WITH THE LEAD WHERE THE LEAD EXITS THE PLASTIC BODY AT THE TOP OF THE PARTING LINE.
4. DIMENSIONS "D1" AND "E1" DO NOT INCLUDE MOLD PROTRUSION. ALLOWABLE PROTRUSION IS .006 PER SIDE. DIMENSIONS "D1" AND "E1" DO INCLUDE MOLD MISMATCH AND ARE DETERMINED AT DATUM PLANE -H-.
5. DIMENSION "b1" DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE .005 TOTAL IN EXCESS OF THE "b1" DIMENSION AT MAXIMUM MATERIAL CONDITION.
6. DATUMS -A- AND -B- TO BE DETERMINED AT DATUM PLANE -H-.
7. DIMENSION "A2" APPLIES WITHIN ZONE "J" ONLY.
8. DIMENSIONS "D" AND "E2" DO NOT INCLUDE MOLD PROTRUSION. OVERALL LENGTH INCLUDING MOLD PROTRUSION SHOULD NOT EXCEED 0.430 INCH FOR DIMENSION "D" AND 0.080 INCH FOR DIMENSION "E2". DIMENSIONS "D" AND "E2" DO INCLUDE MOLD MISMATCH AND ARE DETERMINED AT DATUM PLANE -D-.

## STYLE 1:

PIN 1 – DRAIN  
 PIN 2 – GATE  
 PIN 3 – SOURCE

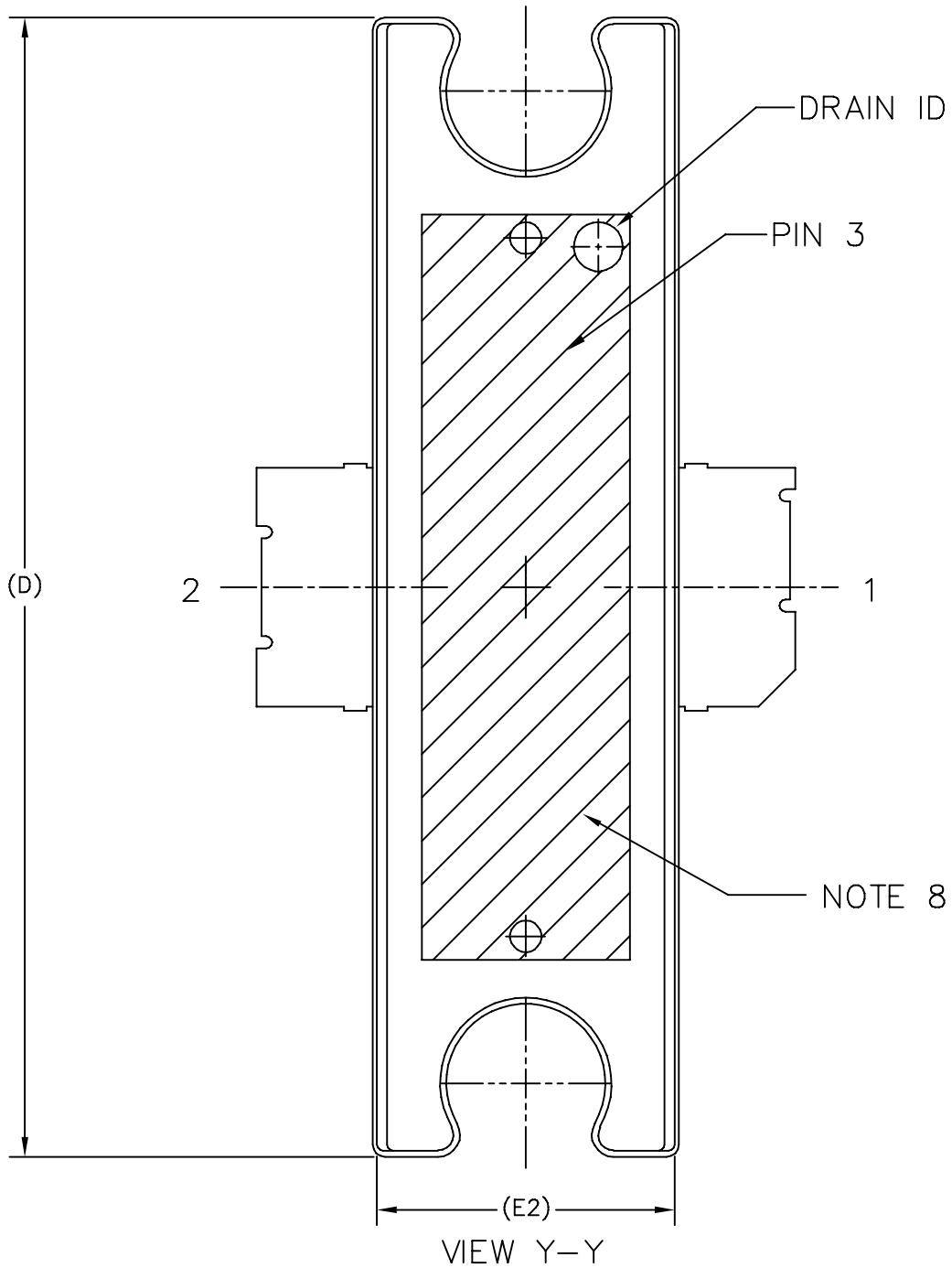
DIM	INCH		MILLIMETER		DIM	INCH		MILLIMETER	
	MIN	MAX	MIN	MAX		MIN	MAX	MIN	MAX
A	.078	.082	1.98	2.08	F	.025	BSC	0.64	BSC
A1	.039	.043	0.99	1.09	b1	.193	.199	4.90	5.06
A2	.040	.042	1.02	1.07	c1	.007	.011	0.18	0.28
D	.416	.424	10.57	10.77	aaa	.004			0.10
D1	.378	.382	9.60	9.70					
D2	.290	.320	7.37	8.13					
D3	.016	.024	0.41	0.61					
E	.436	.444	11.07	11.28					
E1	.238	.242	6.04	6.15					
E2	.066	.074	1.68	1.88					
E3	.150	.180	3.81	4.57					
E4	.058	.066	1.47	1.68					
E5	.231	.235	5.87	5.97					

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TITLE: TO-272 2 LEAD	DOCUMENT NO: 98ASA99191D	REV: C
	CASE NUMBER: 1337-03	21 MAR 2005
	STANDARD: NON-JEDEC	

MRF6V2010NR1 MRF6V2010NBR1



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TITLE:  TO-272 2 LEAD	DOCUMENT NO: 98ASA99191D  CASE NUMBER: 1337-03  STANDARD: NON-JEDEC	REV: C  21 MAR 2005

**MRF6V2010NR1 MRF6V2010NBR1**

NOTES:

1. CONTROLLING DIMENSION: INCH
2. INTERPRET DIMENSIONS AND TOLERANCES PER ASME Y14.5M-1994.
3. DATUM PLANE -H- IS LOCATED AT THE TOP OF LEAD AND IS COINCIDENT WITH THE LEAD WHERE THE LEAD EXITS THE PLASTIC BODY AT THE TOP OF THE PARTING LINE.
4. DIMENSIONS "D" AND "E1" DO NOT INCLUDE MOLD PROTRUSION. ALLOWABLE PROTRUSION IS .006 PER SIDE. DIMENSIONS "D" AND "E1" DO INCLUDE MOLD MISMATCH AND ARE DETERMINED AT DATUM PLANE -H-.
5. DIMENSIONS "b1" DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE .005 TOTAL IN EXCESS OF THE "b1" DIMENSION AT MAXIMUM MATERIAL CONDITION.
6. DATUMS -A- AND -B- TO BE DETERMINED AT DATUM PLANE -H-.
7. DIMENSION A2 APPLIES WITHIN ZONE "J" ONLY.
8. HATCHING REPRESENTS THE EXPOSED AREA OF THE HEAT SLUG.

STYLE 1:  
PIN 1 - DRAIN  
PIN 2 - GATE  
PIN 3 - SOURCE

DIM	INCH		MILLIMETER		DIM	INCH		MILLIMETER	
	MIN	MAX	MIN	MAX		MIN	MAX	MIN	MAX
A	.100	.104	2.54	2.64	b1	.193	.199	4.90	5.05
A1	.039	.043	0.99	1.09	c1	.007	.011	.18	.28
A2	.040	.042	1.02	1.07	r1	.063	.068	1.60	1.73
D	.928	.932	23.57	23.67	aaa		.004		.10
D1	.810 BSC		20.57 BSC						
E	.438	.442	11.12	11.23					
E1	.248	.252	6.30	6.40					
E2	.241	.245	6.12	6.22					
F	.025 BSC		0.64 BSC						

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TITLE:  TO-272 2 LEAD	DOCUMENT NO: 98ASA9919D  CASE NUMBER: 1337-03  STANDARD: NON-JEDEC	REV: C  21 MAR 2005

## PRODUCT DOCUMENTATION

Refer to the following documents to aid your design process.

### Application Notes

- AN1907: Solder Reflow Attach Method for High Power RF Devices in Plastic Packages
- AN1955: Thermal Measurement Methodology of RF Power Amplifiers
- AN3263: Bolt Down Mounting Method for High Power RF Transistors and RFICs in Over-Molded Plastic Packages

### Engineering Bulletins

- EB212: Using Data Sheet Impedances for RF LDMOS Devices

## REVISION HISTORY

The following table summarizes revisions to this document.

Revision	Date	Description
0	Feb. 2007	<ul style="list-style-type: none"><li>• Initial Release of Data Sheet</li></ul>
1	May 2007	<ul style="list-style-type: none"><li>• Corrected Test Circuit Component part numbers in Table 6, Component Designations and Values for C1, C8, C11, C18, C4, C13, C5, and C14, p. 3</li><li>• Corrected Series Impedance <math>Z_{source}</math> and <math>Z_{load}</math> values, Fig. 13, Series Equivalent Source and Load Impedance, p. 7</li></ul>

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